

Hard X-ray Microscope at 10 nm

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The Hard X-ray Nanoprobe (HXN) at the NSLS-II, constructed to achieve the world's most ambitious goal for hard x-ray microscopy, is now ready for general user experiments. The designed microscopy capabilities include measurements of specimen's morphology, composition, crystalline ordering, and chemical states. Intensive R&D for nanofocusing optics [1-3] and nanopositioning [4], together with innovative methods for achieving excellent beam stability, resulted in initial scanning microscopy capability with ~15 nm resolution. The presentation will elaborate on important instrument design features and commissioning experiment results.

References

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